

**Search Notes**

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Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

YAMAKAWA ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	717	6/14/2006	BT
438	722	6/14/2006	BT
438	736	6/14/2006	BT
438	742	6/14/2006	BT
Above	Updated	10/3/2006	BT
Above	Updated	10/3/2006	BT
Above	Updated	10/3/2006	BT
Above	Updated	10/3/2006	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated search using USPAT, USPG-PUB, JPO, EPO, DERWENT database	10/3/2006	BT